

Core-to-Core Program



MEG II実験液体キセノン検出器用VUV-MPPC におけるPDE減少の真空紫外光を用いた調査

**Research on PDE decrease of MPPC for MEG II
liquid xenon detector by using vacuum-ultraviolet**

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On behalf of MEG II collaboration

The University of Tokyo

Mar. 12th, 2021

Introduction

- **The motivation of searching for $\mu \rightarrow e\gamma$**
- **Overview of MEG II**

MPPC

- **MPPC PDE decrease**
- **Surface damage by VUV light**

Measurement of PDE decrease at low-temp

- **Irradiation by xenon flash lamp**
- **Irradiation by liquid xenon scintillation light**

Summary and Prospect

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The motivation of searching for $\mu \rightarrow e\gamma$

- $\mu \rightarrow e\gamma$ in the standard model

$$Br(\mu \rightarrow e\gamma) = \frac{3\alpha}{32\pi} \left| \sum_{i=2,3} U_{\mu i}^* U_{ei} \frac{\Delta m_{i1}^2}{M_W^2} \right|^2 \simeq 10^{-54}$$

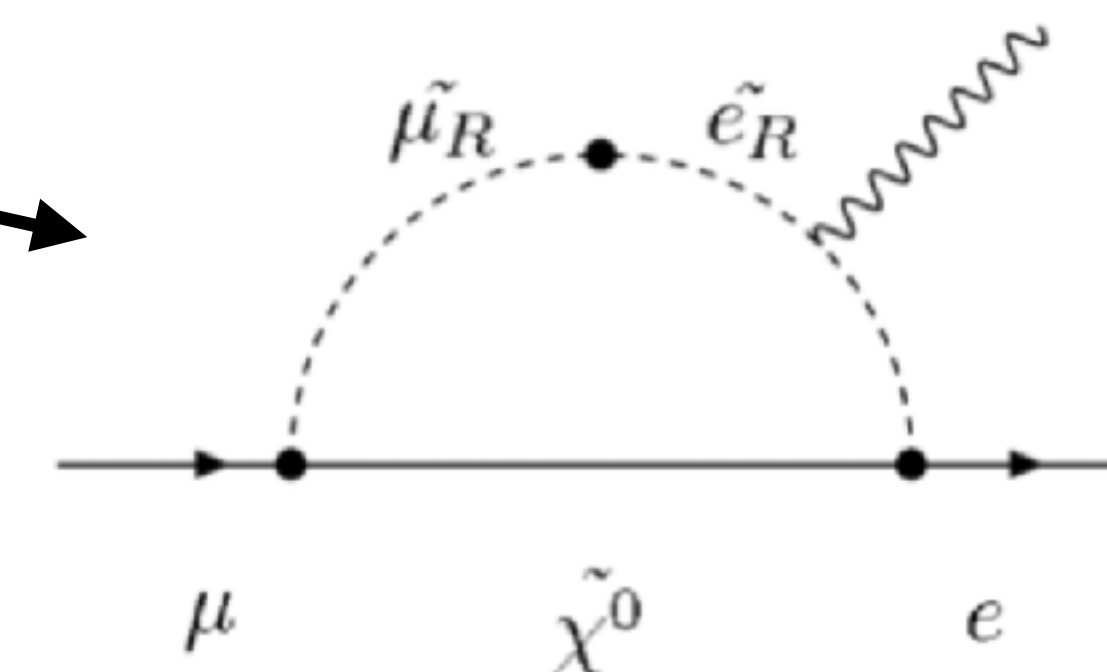
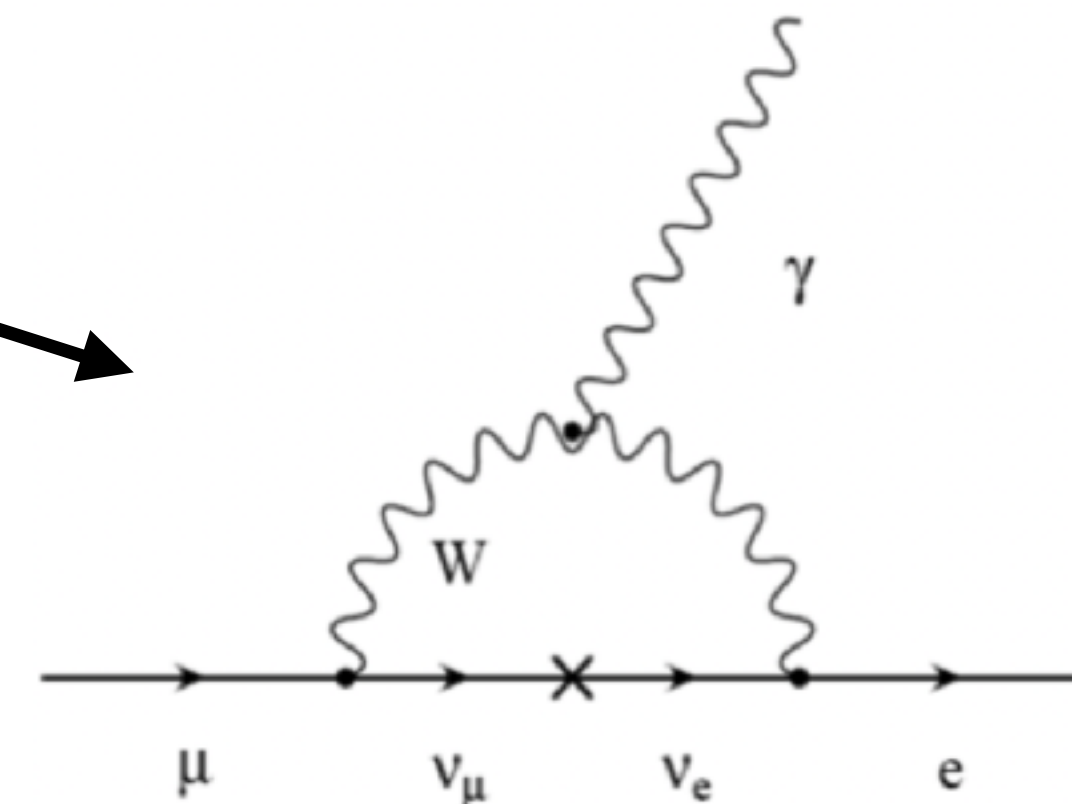
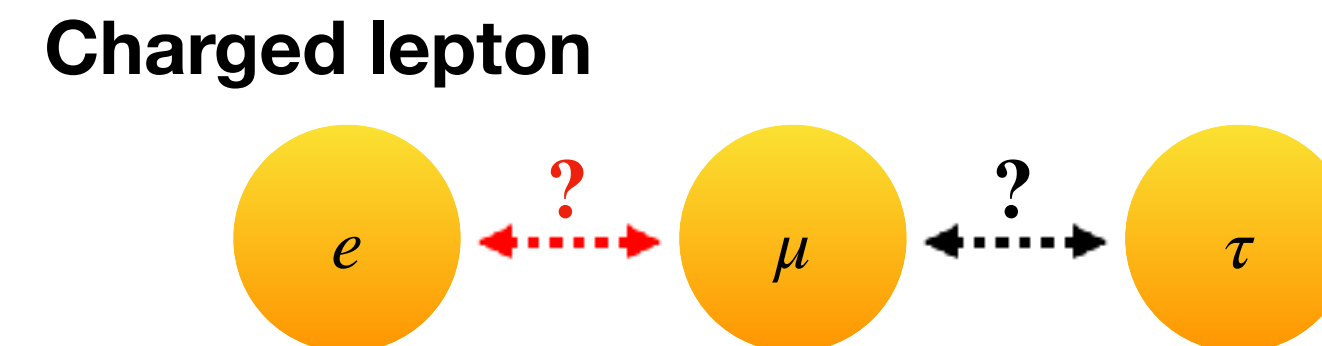
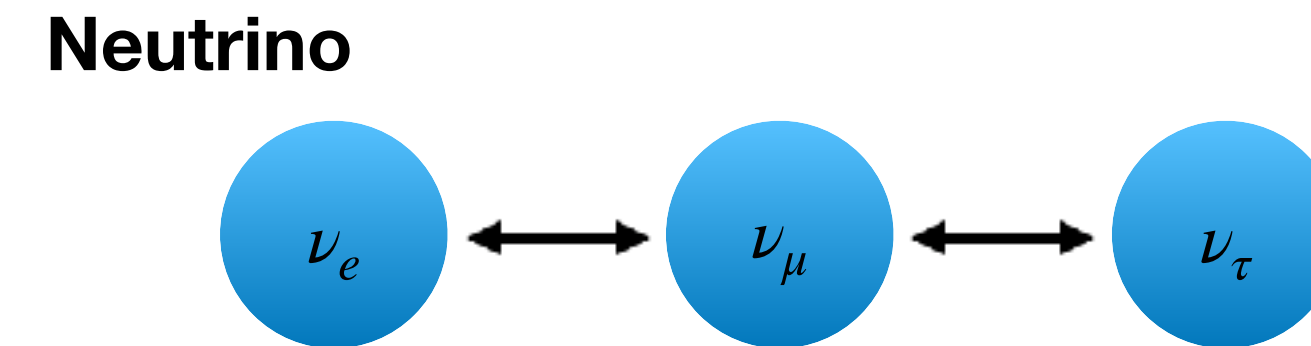
- Cannot be observed

- $\mu \rightarrow e\gamma$ in a new physics e.g. SUSY GUT

- Assume unknown heavy particle

$$Br(\mu \rightarrow e\gamma) = \mathcal{O}(10^{-12}) - \mathcal{O}(10^{-14})$$

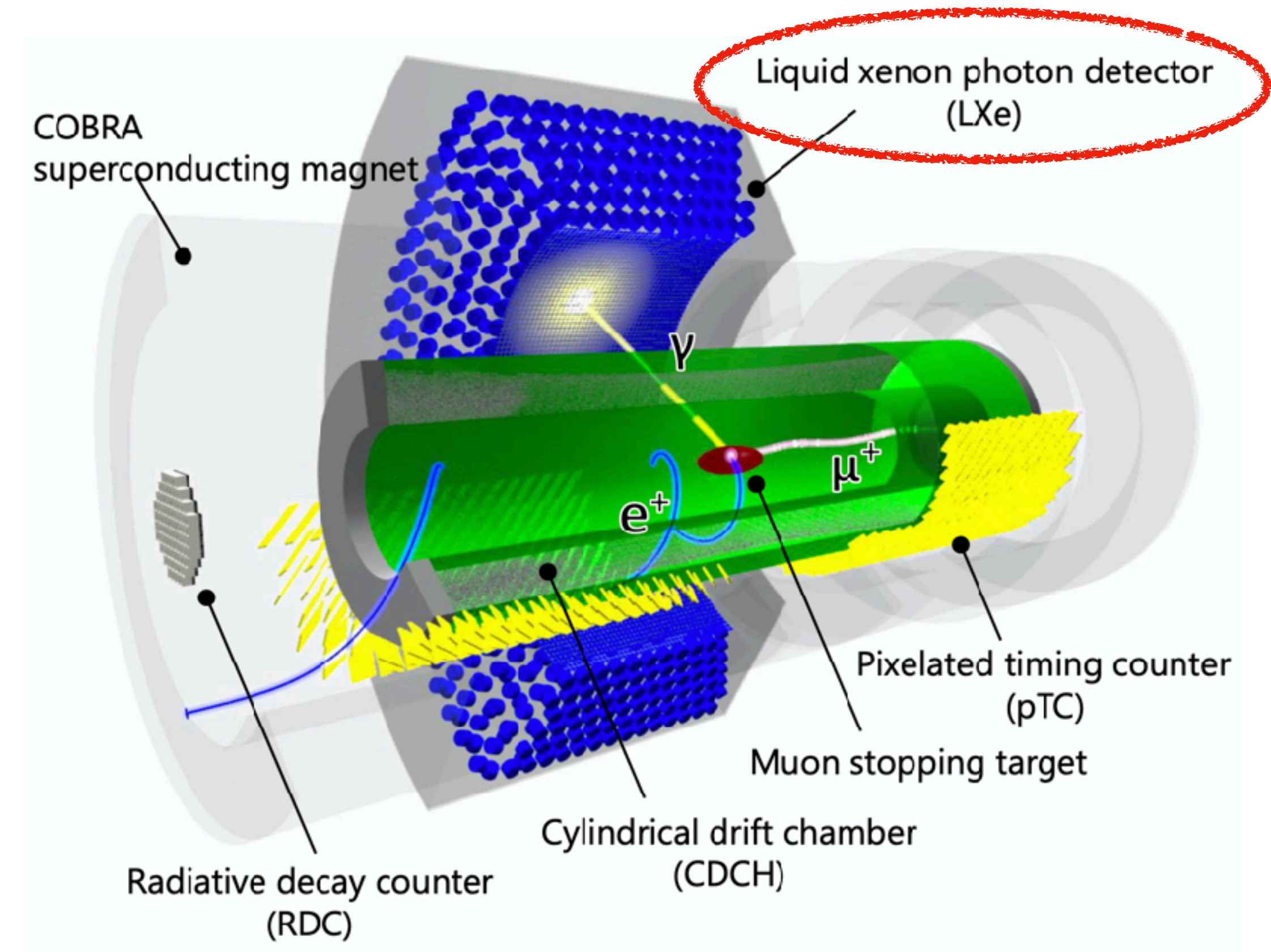
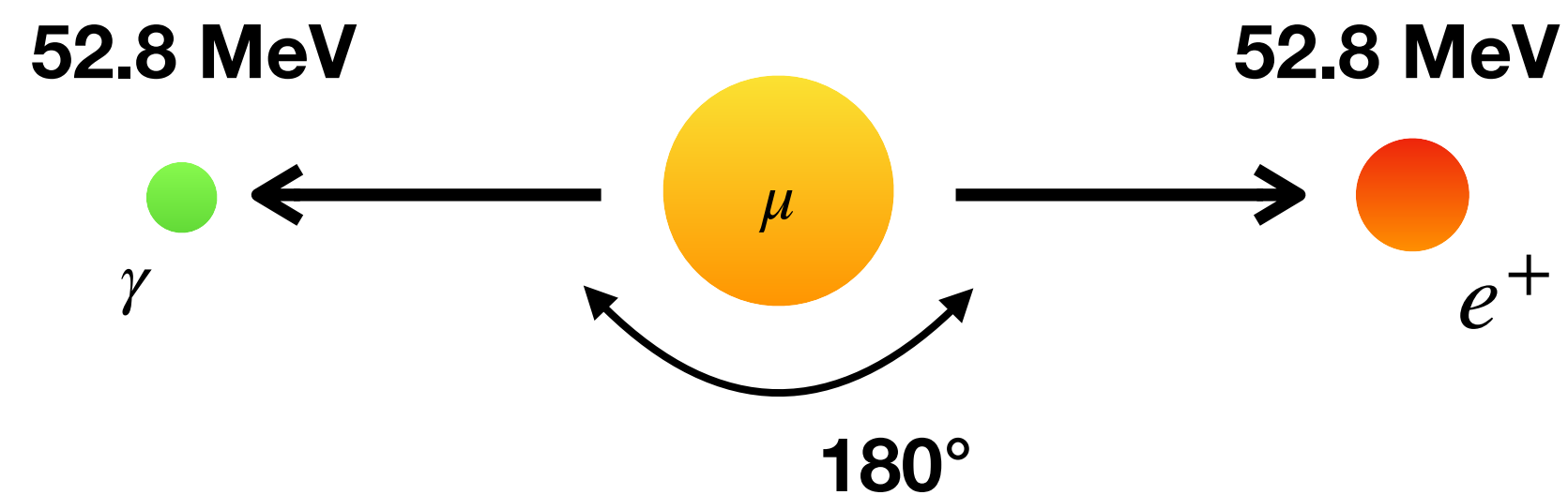
- Can be observed



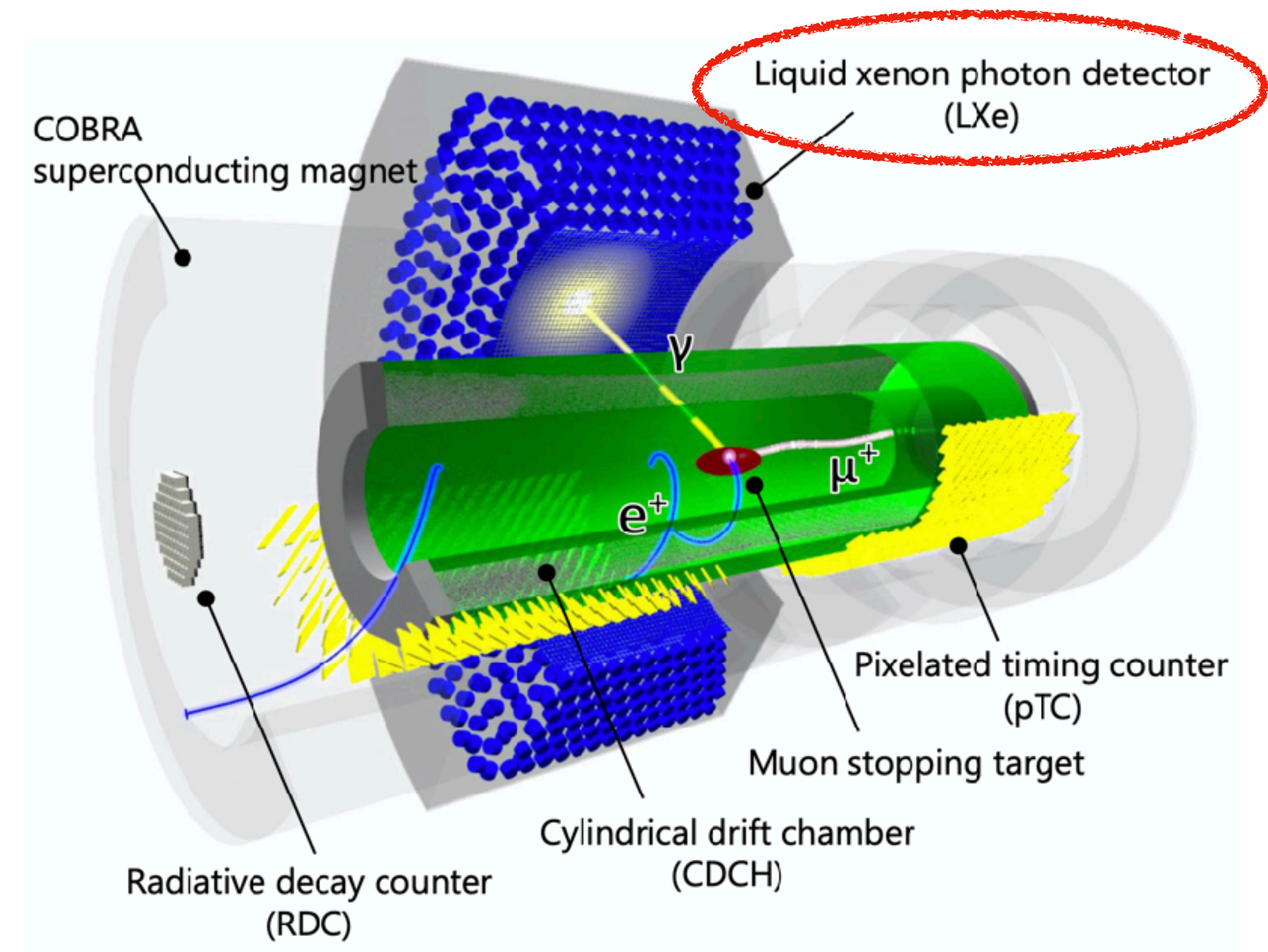
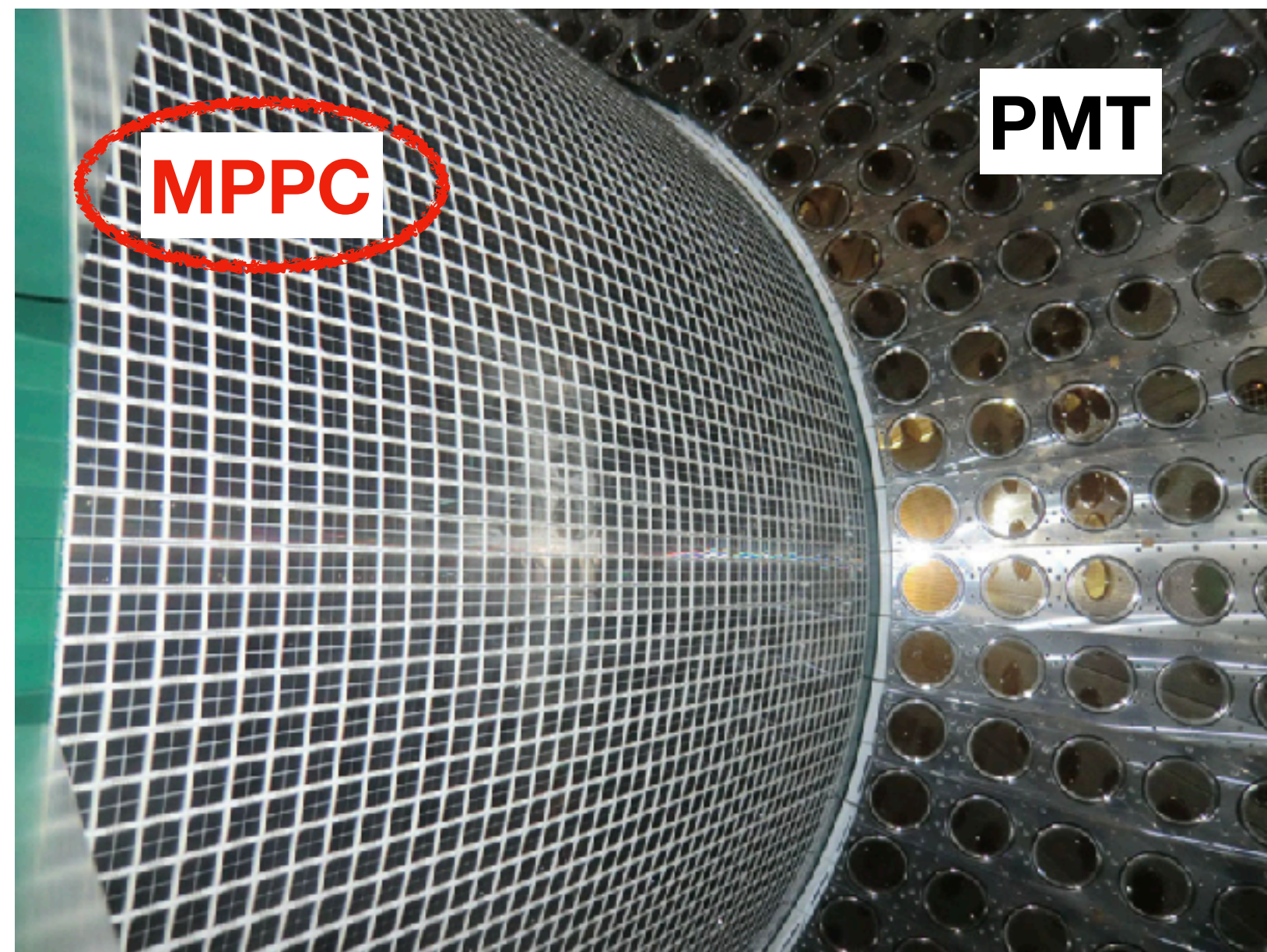
Overview of the MEG II experiment at Paul Scherrer Institut



- The world's most intense μ beam $7 \times 10^7 \mu/\text{sec}$
- Muons are stopped at the target
- Two-body decay
- The photon energy, interaction point and time are measured by LXe



Overview of the MEG II experiment at Paul Scherrer Institut



- Detect the scintillation ($\lambda = 175$ nm)
- 4092 **MPPCs**, 668 PMTs at ~ 165 K
- Energy and position resolutions will be improved as compared with MEG by a factor of two
- Under commissioning since 2017

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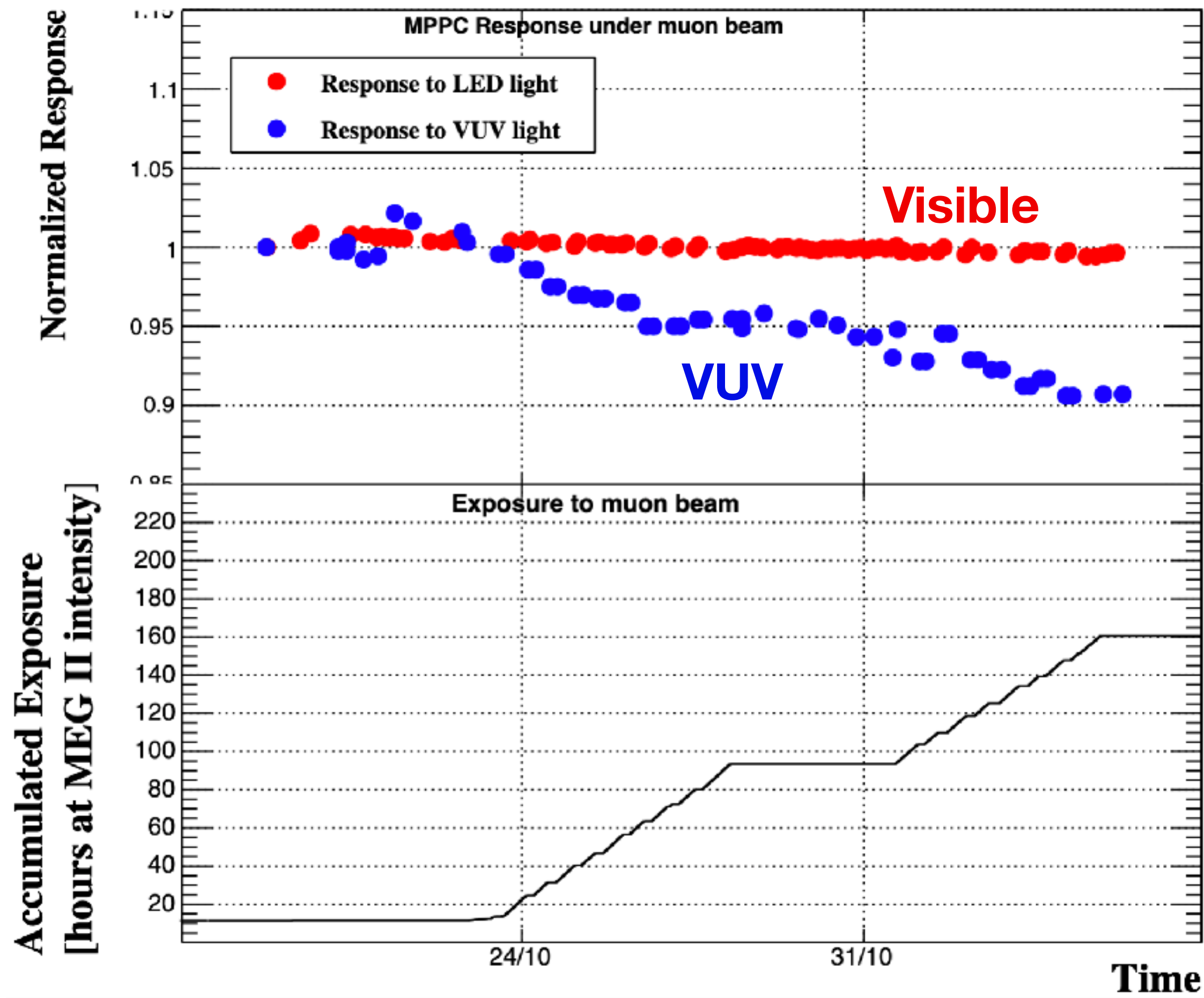
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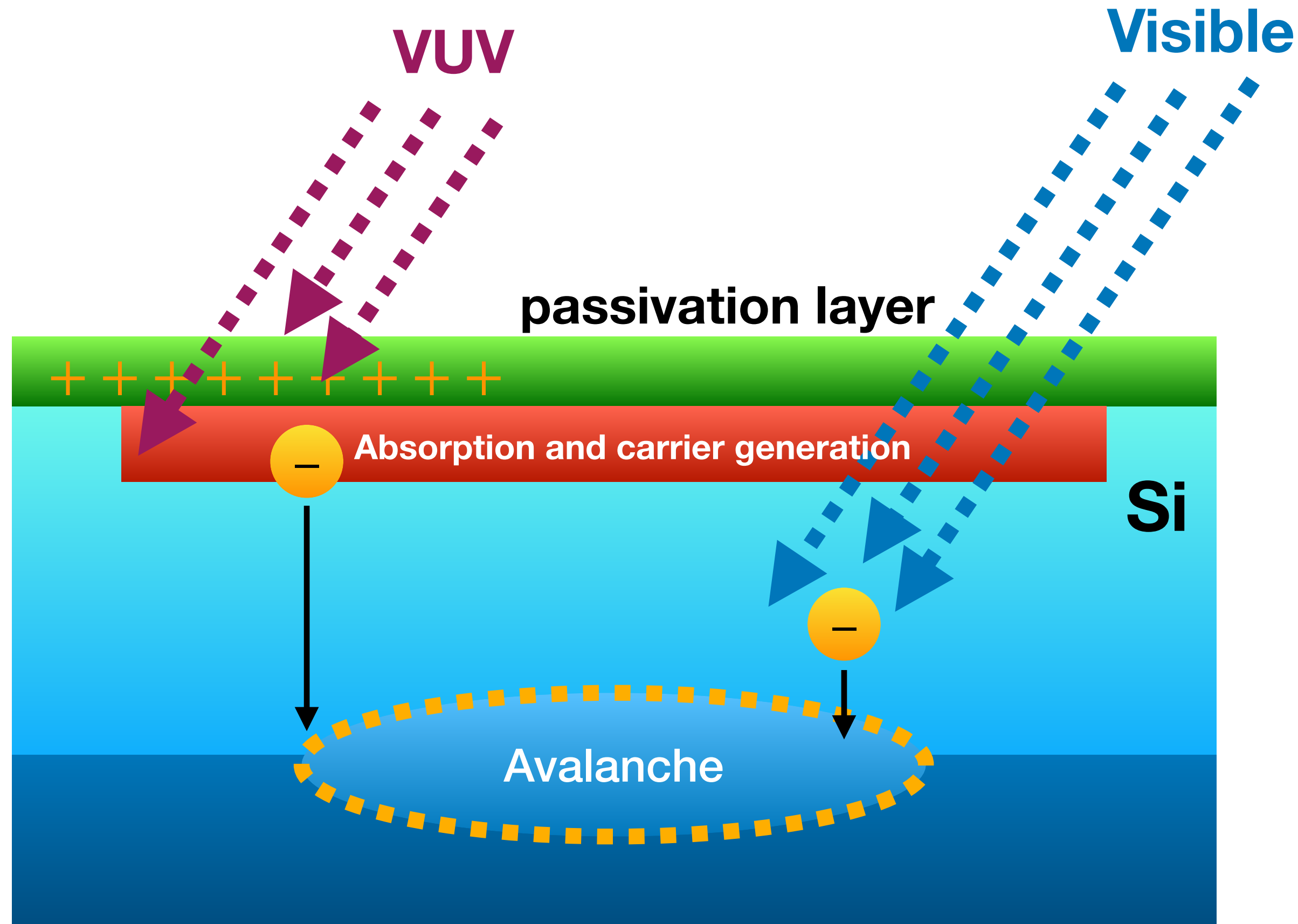
Summary and Prospect

VUV-sensitive MPPC PDE decrease



- Photon detection efficiency (PDE)
- Visible sensitivity was almost unchanged
- Degradation of VUV sensitivity
 → Total decrease in 2019 : 9%
 (in 1 week under MEG II beam intensity $7 \times 10^7 \mu/\text{sec}$)
- Design MEG II DAQ time : 360days (3 years)
 → This degradation is a serious problem

Possible cause : surface damage by VUV light



- Surface damage was observed in other experiments
- Most VUV light pass through the passivation layer (e.g. SiO_2), but some of them stopped in it
 - Electron-holes are generated in passivation layer
- Holes are trapped at interface b/w passivation layer and Si
- The electric field near the boundary of the two surfaces will be reduced by the holes
 - Collection efficiency will be reduced
- Degradation may be accelerated **at low temperature** because holes hardly move
- Holes will be removed by heat
 - Annealing effect was observed

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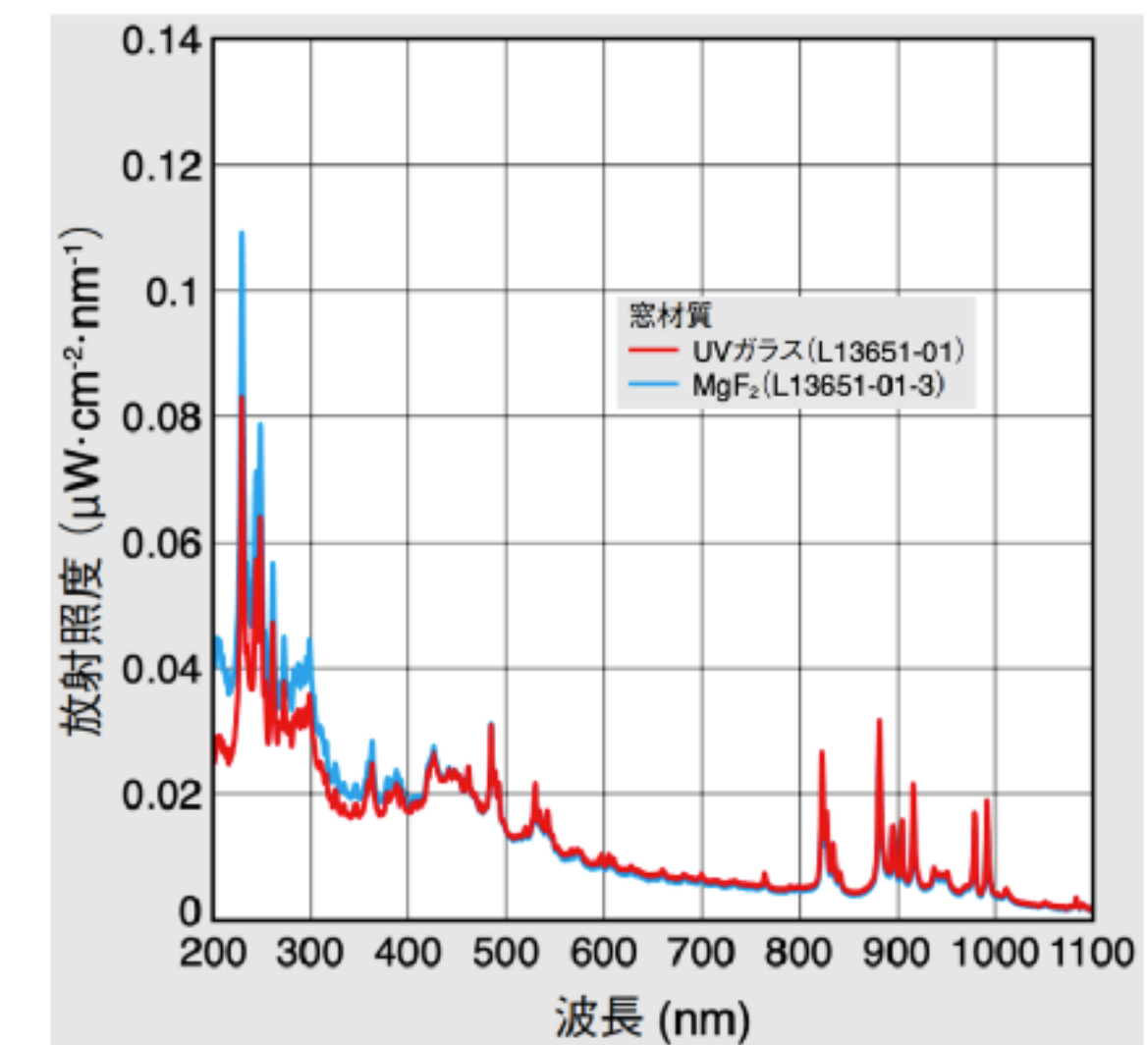
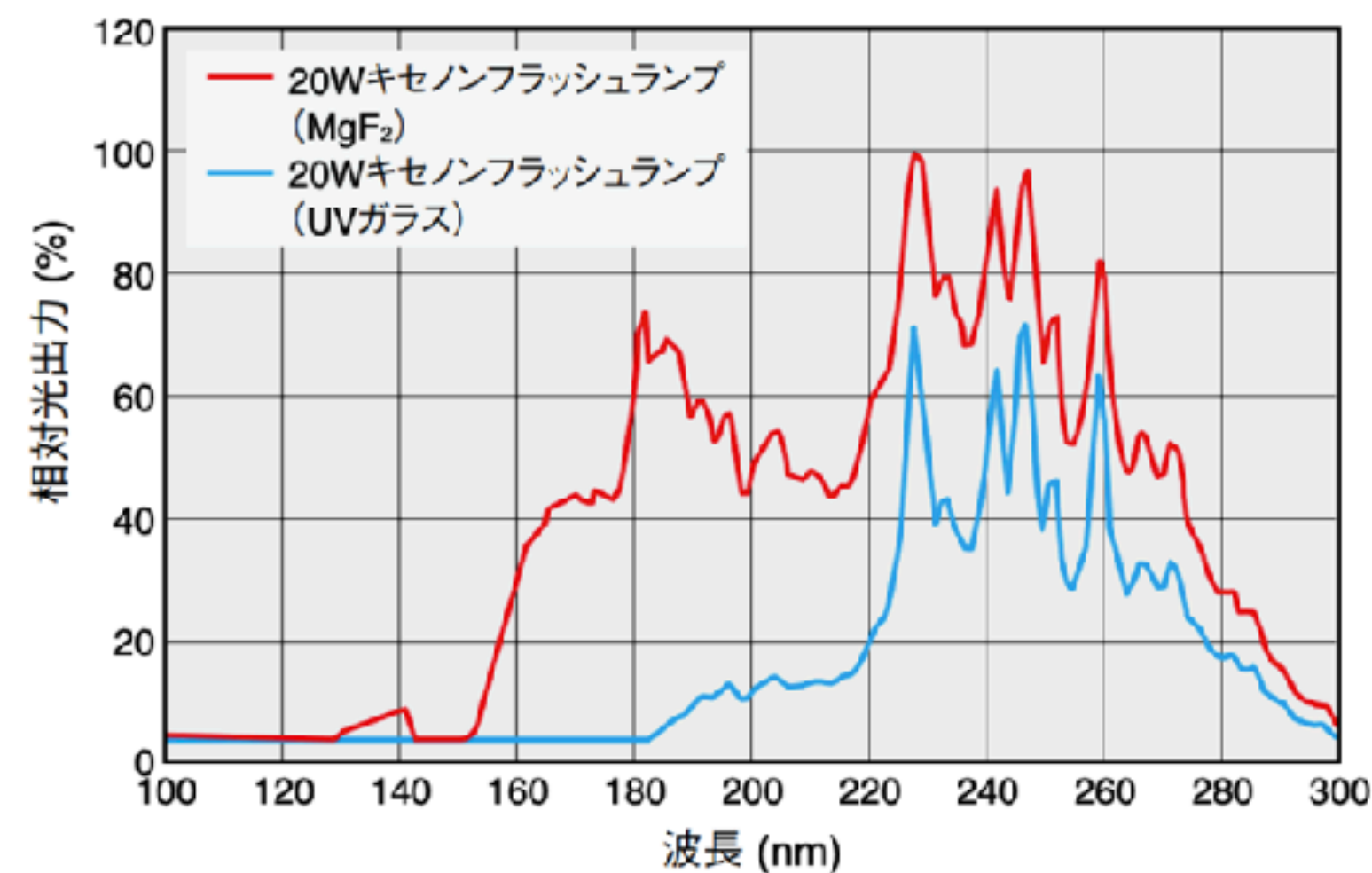
Summary and Prospect

Overview of the measurements

- We want to know how PDE decreases in MEG II DAQ time
- PDE decrease by UV and low-temp effect were observed in previous measurement (15pSF-5)
 - Much slower than MEG II LXe detector
 - There may be wave length effect
- This time, MPPCs were irradiated by VUV at ~165 K
- Irradiation source
 - Xe flash lamp
 - Xe scintillation light

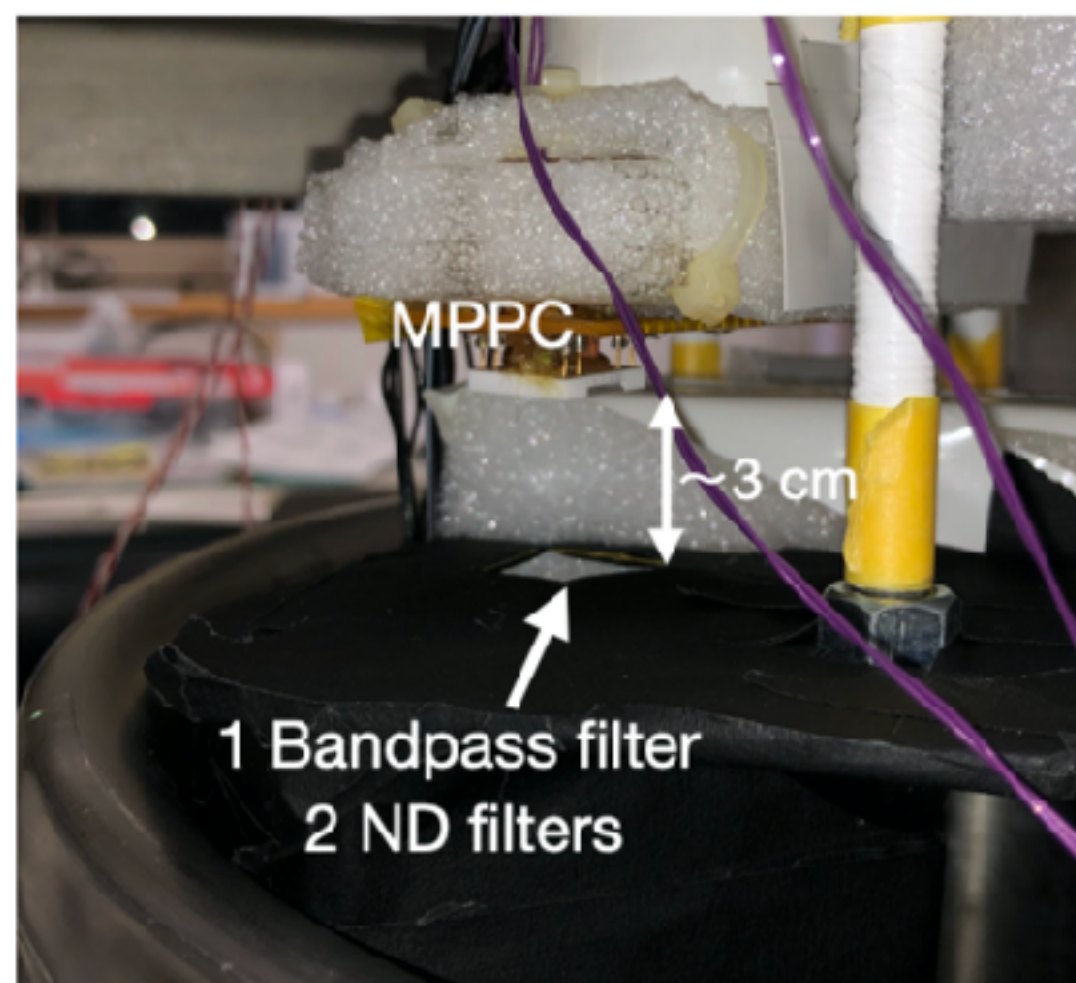


Xe-lamp 2 W module
(L13651-01-3)

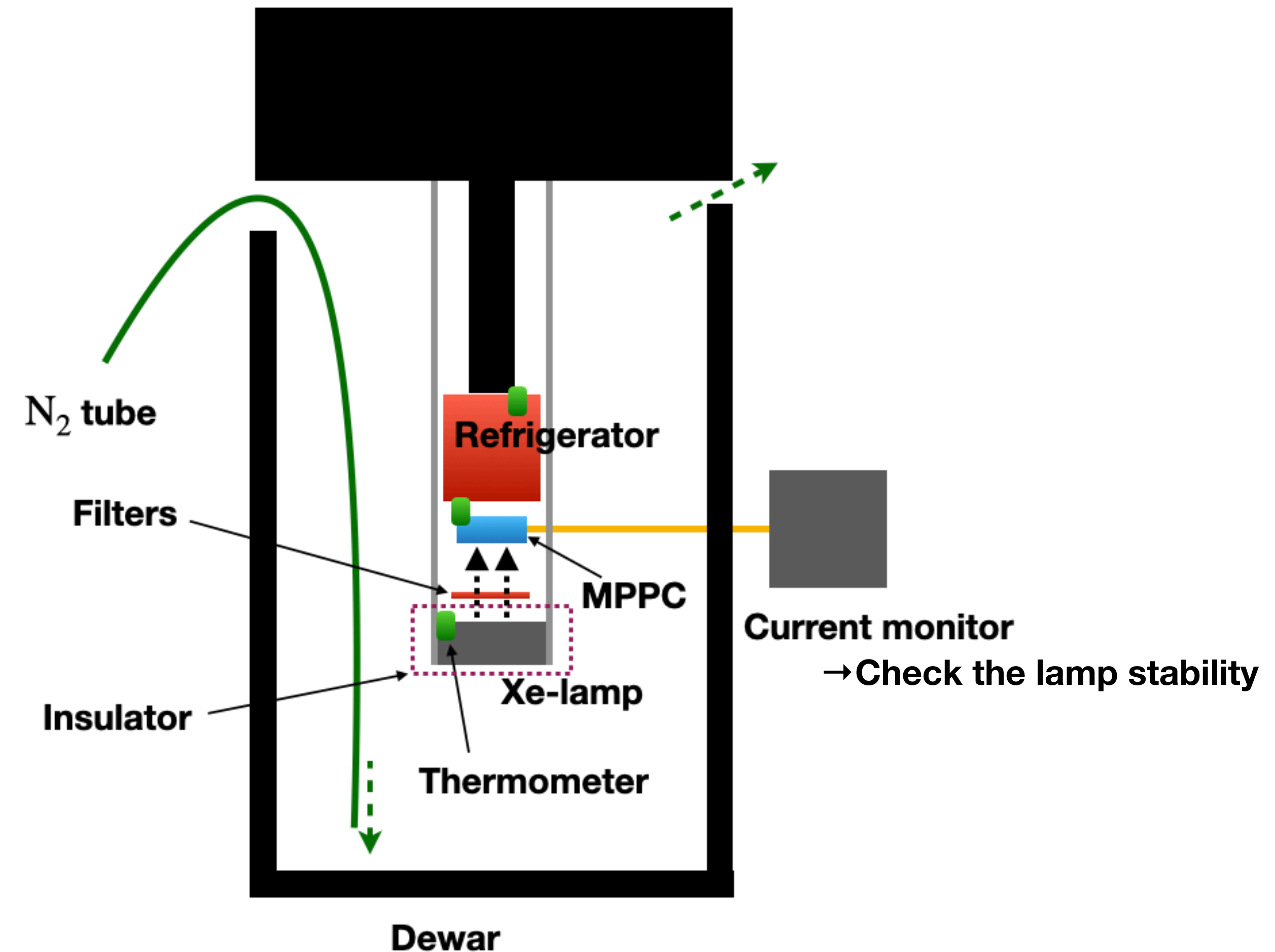


Irradiation by Xe-lamp

- Irradiation source : Xe-lamp (MgF₂ glass)
- Cooled the MPPC in N₂ gas
 - Prevent dew formation
 - Allows VUV to reach MPPC
 - Absorption length of N₂ is smaller by ~2 orders of magnitude than that of O₂
- MPPC was mounted on refrigerator
 - MPPC temp ~ 165 K

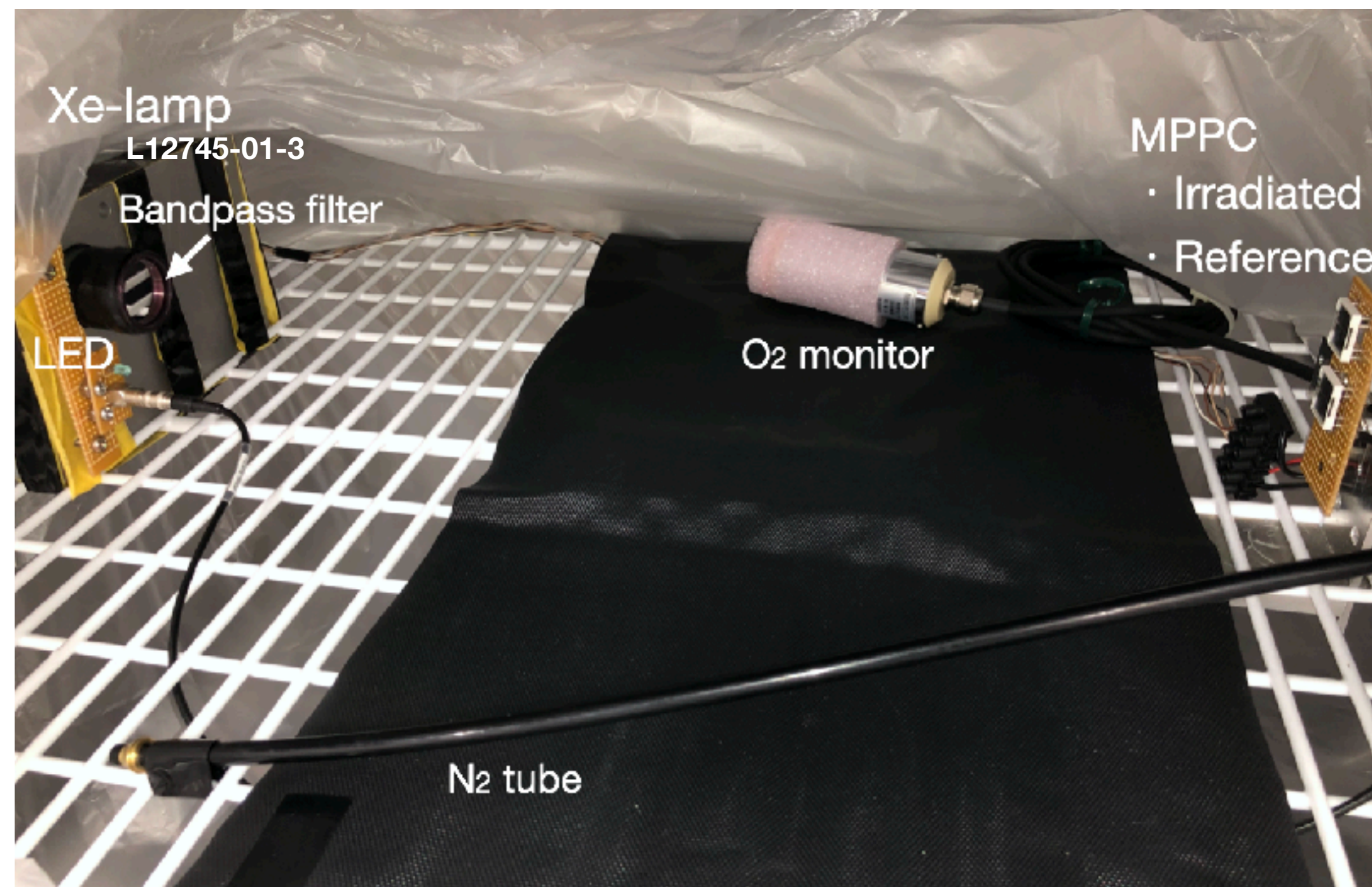


Overview of setup : Irradiation

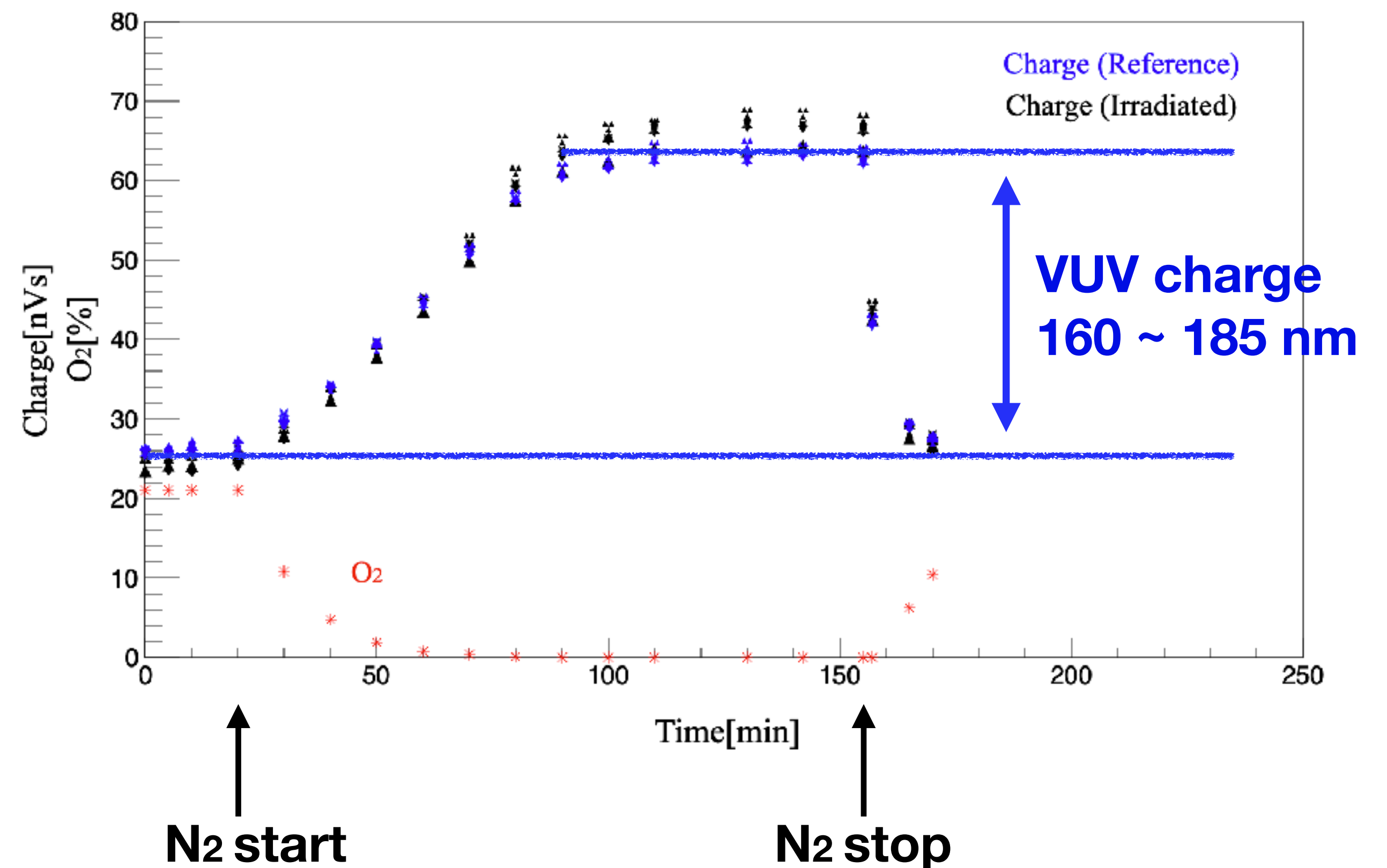


Irradiation by Xe-lamp

- Signal charge was measured before and after the irradiation
- Non irradiated MPPCs were also used as reference



- Observed VUV charge by using N₂ gas
 - Absorption cross section of 175 nm is largely different b/w O₂ and N₂



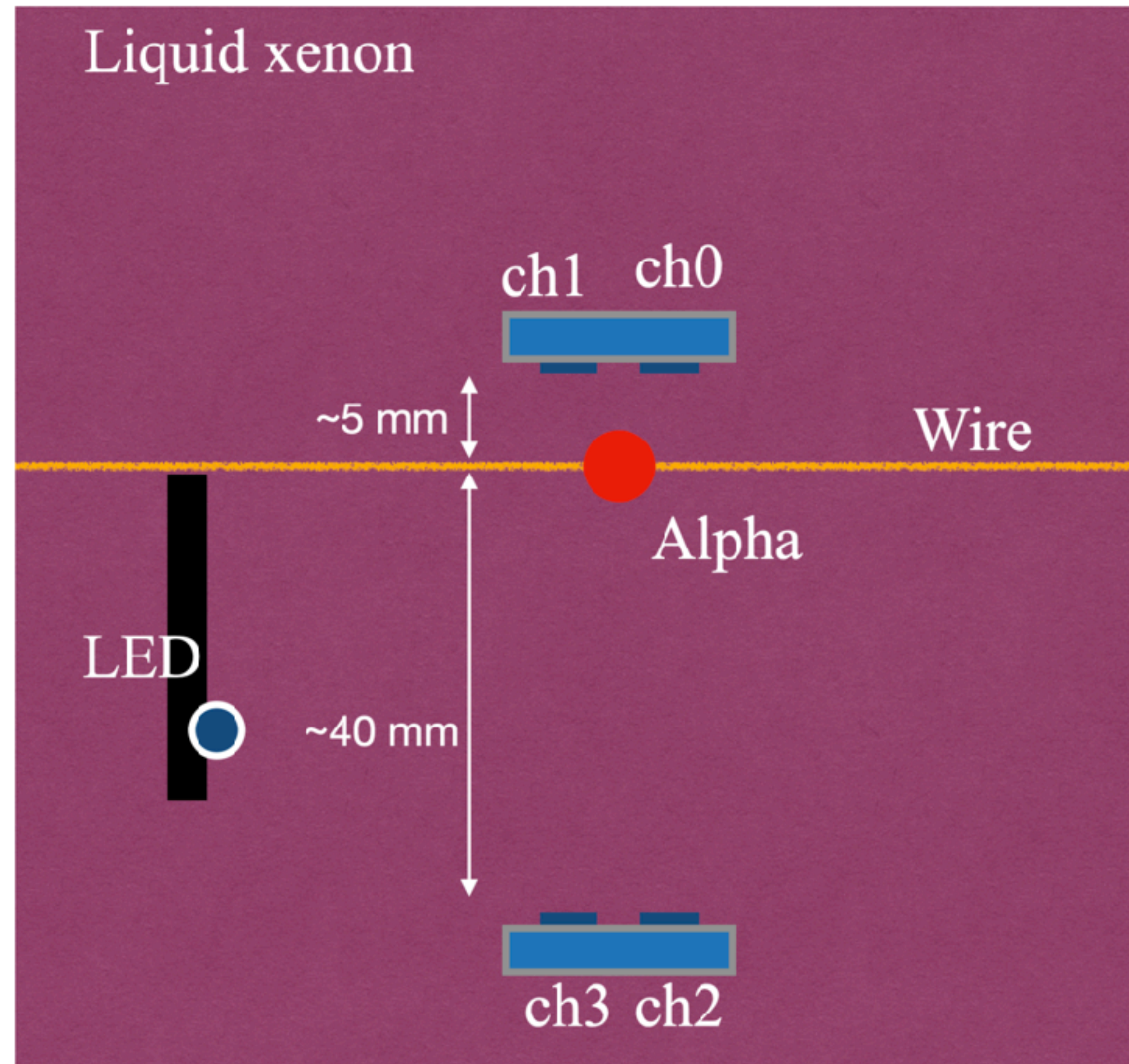
VUV irradiation at low-temp

$\text{PDE}_{\text{after}}/\text{PDE}_{\text{before}}$

	chip 1	chip 2	chip 3	chip 4
Reference	1.06	1.07	1.11	1.08
Irradiated	1.16	1.17	1.17	1.15

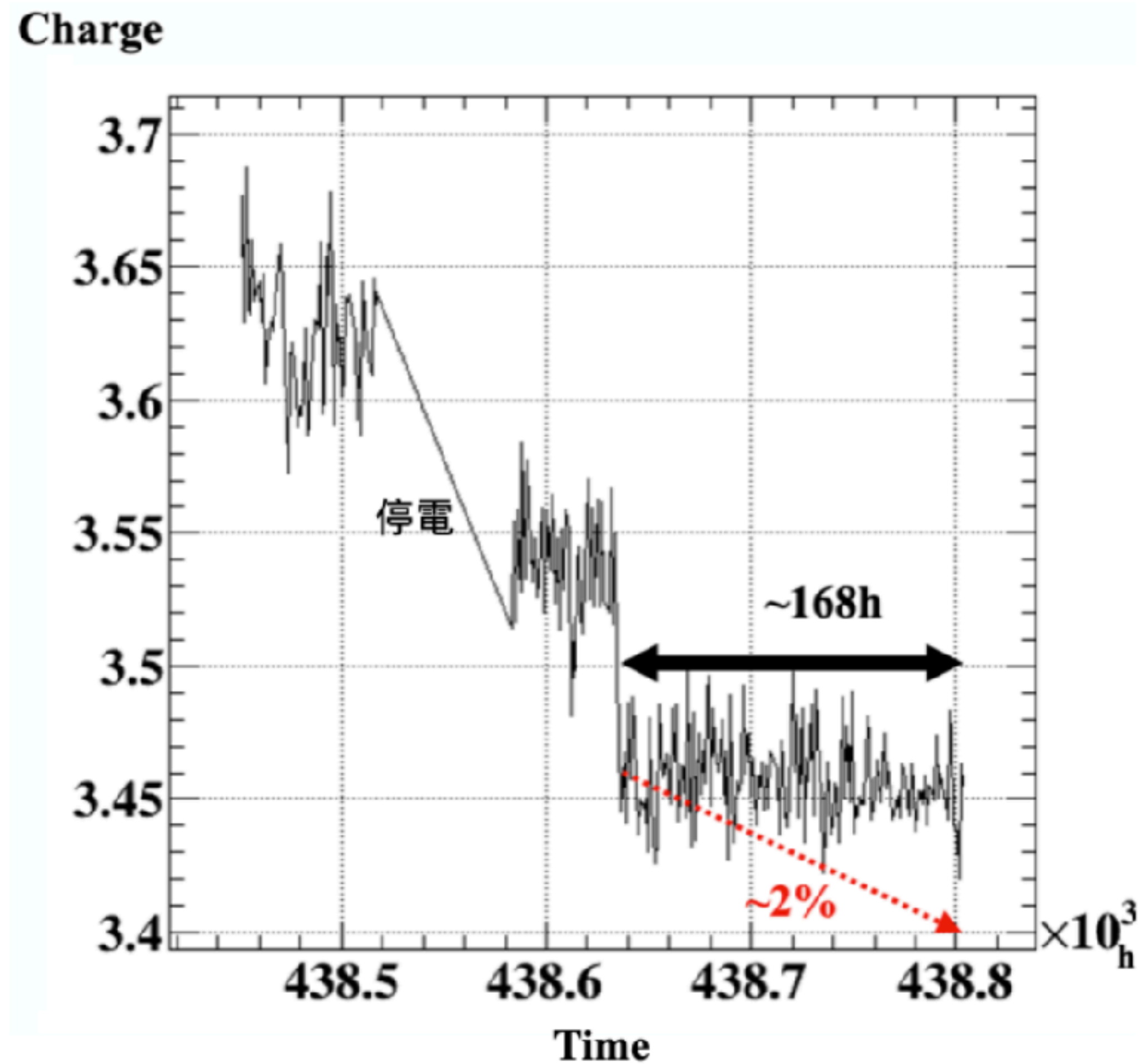
- N_{VUV} : **Dose level in this measurement**
- $N_{2019,VUV}$: **Dose level in LXe detector in 2019**
- **Dose level (in 21 h) : $160 \text{ nm} \lesssim \lambda \lesssim 185 \text{ nm}$**
 - $N_{VUV} = 1.7 \times 10^{11} \text{ photon/mm}^2$
 $= N_{2019,VUV} \times 3.3$
→Corresponds to ~ 30% decrease
- **VUV-PDE decrease was not observed**

Irradiation by liquid xenon scintillation light using alpha sources



- **Light source : liquid xenon scintillation light**
 - **Alpha source (^{241}Am , range : $50\text{ }\mu\text{m}$) was set in liquid xenon**
 - **Dose level is smaller than Xe-lamp**
 - **Other conditions are the same as LXe detector**
- **Signal charge was monitored**
- **LED was set for calibration and monitoring visible sensitivity**

Irradiation by liquid xenon scintillation light using alpha sources



- The data in last 168 h was stable
- Signal charge for LED was not changed
- Dose level (in 168 h) : $\lambda = 175 \text{ nm}$
 - $N_{VUV} = 1.6 \times 10^{10} \text{ photon/mm}^2$
 $= N_{2019,VUV} \times 0.31$
- In all chips, VUV-PDE decrease was not observed

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- In MEG II LXe detector, VUV-PDE decrease was observed
 - It was guessed that the degradation was caused by surface damage

- Irradiation measurements were performed
 - PDE decrease by UV was observed in previous measurement

$$N_{UV} \gg N_{2019,VUV}$$

- VUV-sensitivity degradation was not observed

$$N_{VUV} \sim N_{2019,VUV}$$

→ VUV photon is not the main cause of the VUV-PDE decrease of the MPPCs in LXe detector

- Irradiation by excimer lamp is going to be performed

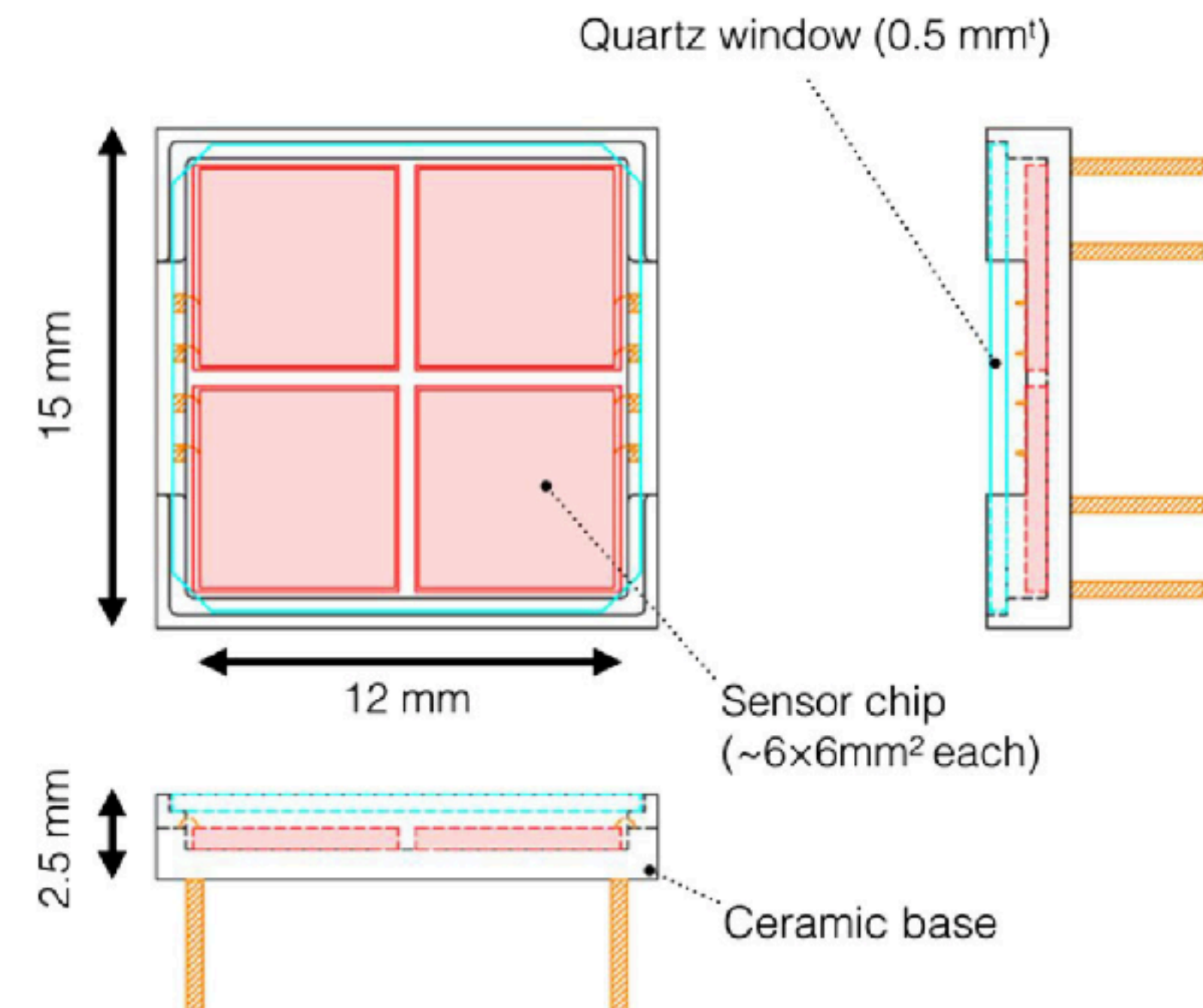
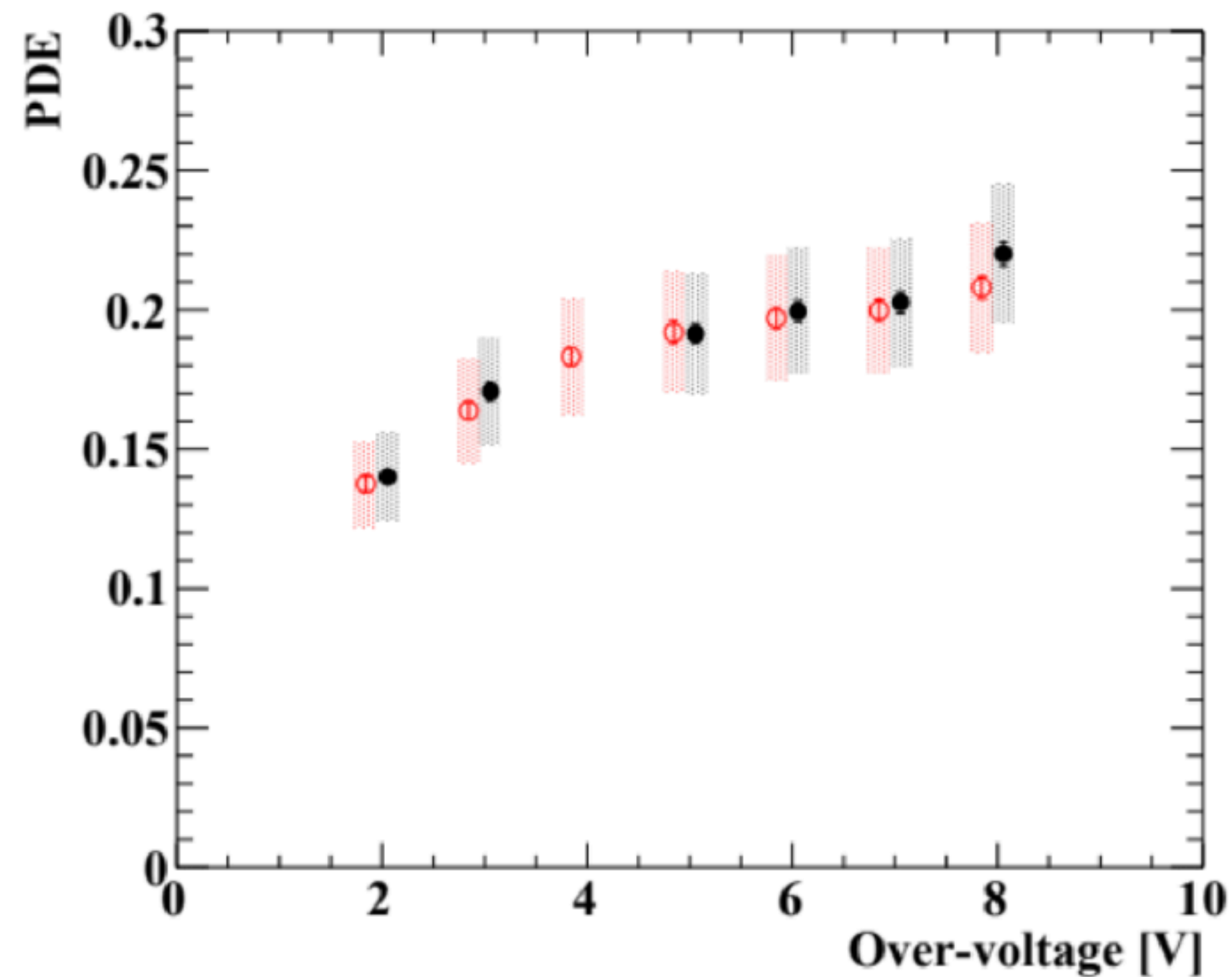
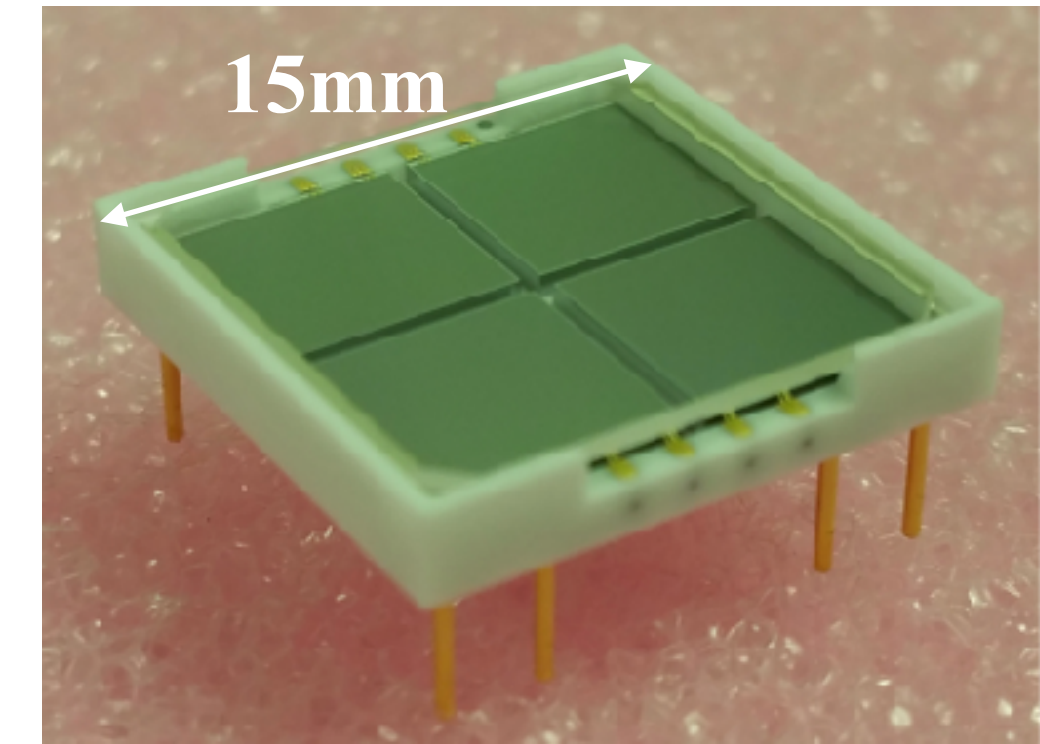
- $N_{2019,VUV} \times 10^3/\text{sec}$ at 5 cm ($\lambda = 172$ nm)

- Other candidates
 - MPPCs in LXe detector were irradiated γ and neutron
 - We are now investigating this effect (next talk 12pT2-9)

Backup slides

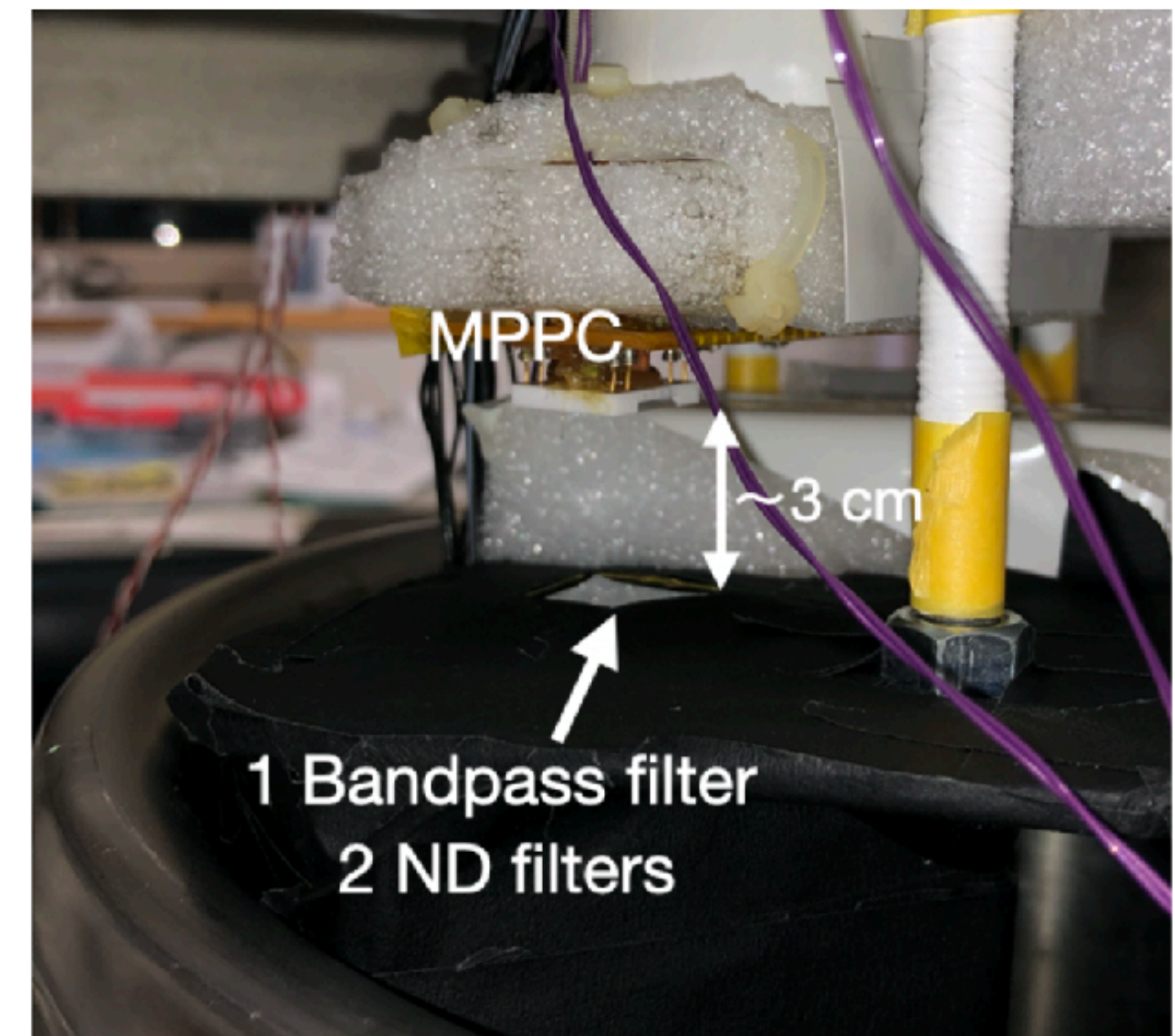
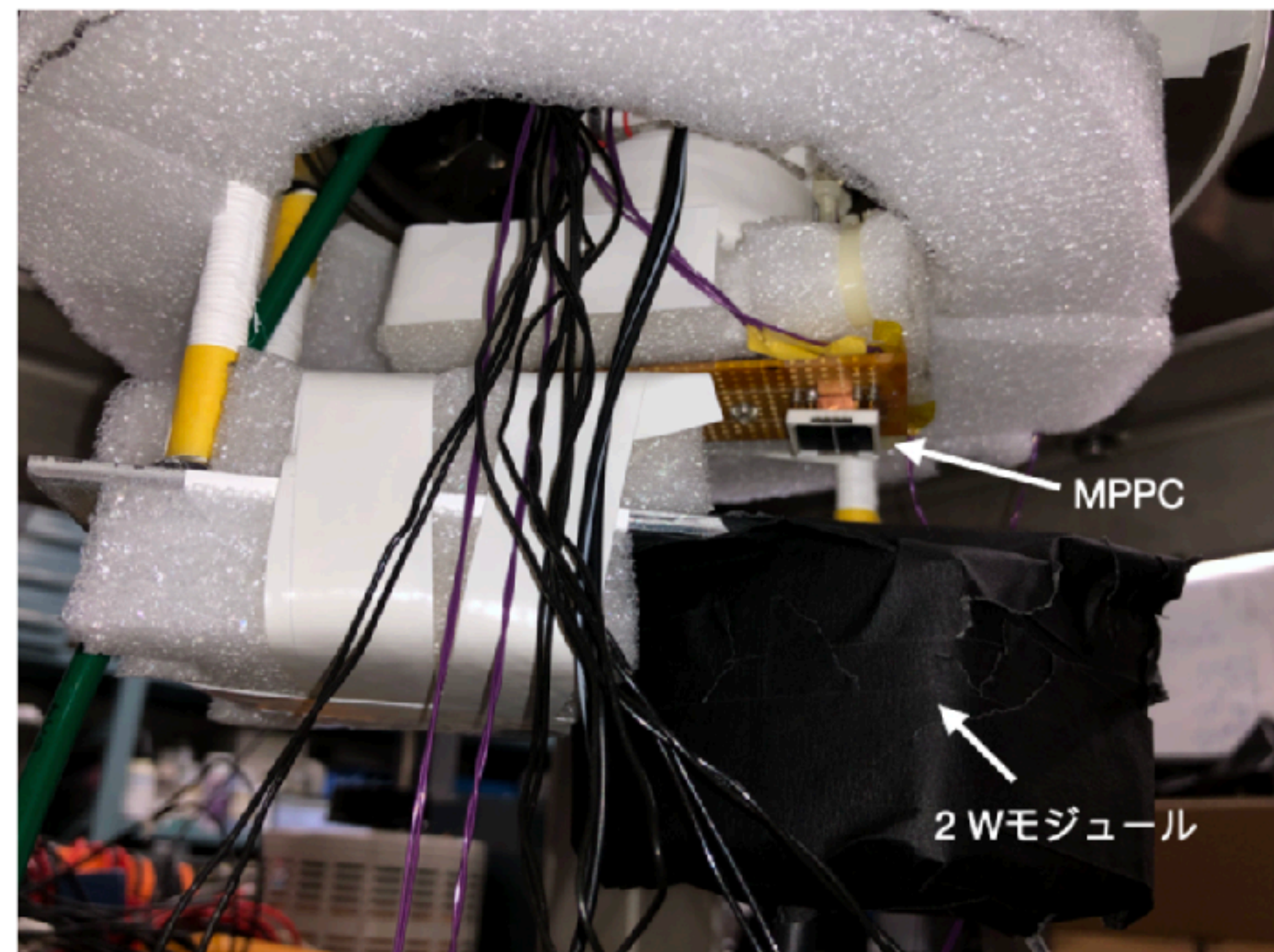
VUV-sensitive MPPC (SiPM)

- VUV-sensitive MPPC has been newly developed for MEG II
- Operational at low temperature (~ 165 K)
- Photon detection efficiency (PDE) $> 15\%$ at $\lambda = 175\text{nm}$



VUV irradiation at low-temp

- Light source : Xe-lamp (MgF₂ glass)
- Cooled the MPPC in N₂ gas
 - MPPC was mounted on refrigerator
- Signal charge was monitored
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